

Albert Byun, Lead Engineer for Microelectronics, General Electric Research Center

Role/Expertise: Mixed-signal circuit design, Micro-Electro-Mechanical System

Citizenship: United States of America

Clearances: None

Education: Georgia Institute of Technology, M.S. Electrical Engineering; 2007
The Ohio State University, M.S. Electrical Engineering; 2005

Relevant Experience: Mr. Byun has served a variety of research and development activities during his 13-year tenure at GE Research: including a mix of contributor and leadership responsibilities. Most recently, Mr. Byun is the project leader for next-generation MRI receiver electronics development. His past expertise includes developing application-specific-integrated-circuits for GE Healthcare imaging modalities such as CT, Ultrasound, X-ray and PET/MR and electronics for Neutron and Volatile Organic Compounds detectors for DARPA. His other expertise includes developing control electronics for MEMS devices such as microswitch and gyroscopes.